

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re: Stefan Schek Confirmation No: 4430
Application No: 10/501,686 Art Unit: 2182
Filed: December 29, 2005 Examiner: Sorrell, Eron J.
For: Method for Data Processing in
a Scan Microscope Comprising
a Fast Scanner and Scan
Microscope Comprising a Fast
Scanner
Customer No.: 29127
Attorney Docket No. 21295.87 (E0614US)

AMENDMENT AND RESPONSE AFTER FINAL ACTION

Mail Stop AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In response to the pending final Office Action, mailed November 20, 2009, (Paper No. 20091109), please amend the above-identified patent application as follows:

Amendments to the Claims are reflected in the listing of claims in the Amendments to the Claims section.

Reconsideration is requested in view of the remarks set forth in Remarks/Arguments section.

A one-month extension is requested for this response.